



MUX-08/MUX-24

8-CHANNEL/DUAL 4-CHANNEL JFET ANALOG MULTIPLEXERS

(OVERVOLTAGE AND POWER SUPPLY LOSS PROTECTED)

Precision Monolithics Inc.

FEATURES

- JFET Switches Rather Than CMOS
- Low "ON" Resistance 220Ω Typ
- Highly Resistant to Static Discharge Damage
- No SCR Latch-Up Problems
- Digital Inputs Compatible With TTL and CMOS
- 125°C Temperature Tested Dice Available
- MUX-08 Pin Compatible With DG508, HI-508A, IH5108, IH6108, LF11508/12508/13508, AD7506
- MUX-24 Pin Compatible With DG509, HI-509A, IH5208, IH6208, LF11509/12509/13509, AD7507
- Available in Surface Mount Packages
- Available in Die Form

ORDERING INFORMATION †

25°C ON RESISTANCE	PACKAGE			OPERATING TEMPERATURE RANGE
	CERDIP 16-PIN	PLASTIC 16-PIN	LCC 20-CONTACT	
220Ω	MUX08AQ*	—	—	MIL
	MUX08EQ	—	—	IND
	—	MUX08EP	—	COM
300Ω	MUX08BQ*	—	MUX08BRC/883	MIL
	MUX08FQ	—	—	IND
	—	MUX08FP	—	XIND
	—	MUX08FS††	—	XIND
220Ω	MUX24AQ*	—	—	MIL
	MUX24EQ	—	—	IND
	—	MUX24EP	—	COM
300Ω	MUX24BQ*	—	—	MIL
	MUX24FQ	—	—	IND
	—	MUX24FP	—	XIND
	—	MUX24FS††	—	XIND

* For devices processed in total compliance to MIL-STD-883, add /883 after part number. Consult factory for 883 data sheet.

† Burn-in is available on commercial and industrial temperature range parts in CerDIP, plastic DIP, and TO-can packages. For ordering information, see PMI's Data Book, Section 2.

†† For availability and burn-in information on SO and PLCC packages, contact your local sales office.

GENERAL DESCRIPTION

The MUX-08 is a monolithic eight-channel analog multiplexer which connects a single output to one of the eight analog inputs depending upon the state of a 3-bit binary address.

The MUX-24 is a monolithic four-channel differential analog multiplexer configured in a double pole, four-position (plus OFF) electronic switch array. A two-bit binary input address connects a pair of independent analog inputs from each four-channel input section to the corresponding pair of independent analog outputs.

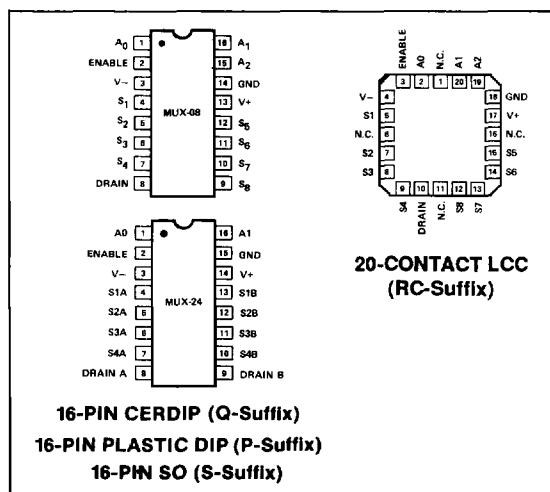
All switches in the MUX-08/MUX-24 are turned OFF by applying logic "0" to the ENABLE pin, thereby providing a package select function.

Fabricated with Precision Monolithics' high performance Bipolar-JFET technology, these devices offer low, constant "ON" resistance, low leakage currents and fast settling time

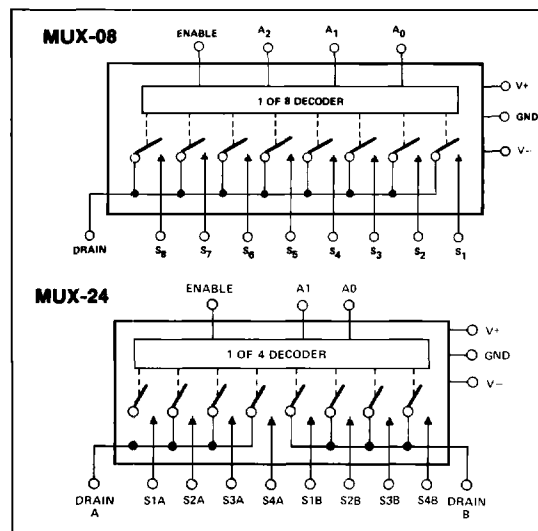
with low crosstalk to satisfy a wide variety of applications. These multiplexers do not suffer from latch-up or static charge blow-out problems associated with similar CMOS parts. The digital inputs are designed to operate from both TTL and CMOS levels while always providing a definite break-before-make action without the need for external pull-up resistors over the full operating temperature range.

For single sixteen-channel and dual eight-channel models, refer to the MUX-16/MUX-28 data sheet.

PIN CONNECTIONS



FUNCTIONAL DIAGRAMS



ABSOLUTE MAXIMUM RATINGS (Note 1)

Operating Temperature Range	
MUX-08/24-AQ, BQ, BRC	-55°C to +125°C
MUX-02/24-EQ, FQ	-25°C to +85°C
MUX-08/24-EP	0°C to +70°C
MUX-08/24-FP, FS	-40°C to +85°C
Junction Temperature (T _J)	-65°C to +150°C
Storage Temperature Range	-65°C to +150°C
P-Suffix	-65°C to +125°C
Lead Temperature (Soldering, 60 sec)	300°C
Maximum Junction Temperature	150°C
V ₊ Supply to V ₋ Supply	36V
Logic Input Voltage	(-4V or V ₋) to V ₊ Supply

Analog Input Voltage V₋ Supply -20V to V₊ Supply +20V
 Maximum Current Through Any Pin 25mA

PACKAGE TYPE	Θ _{JA} (Note 2)	Θ _{JC}	UNITS
16-Pin Hermetic DIP (Q)	100	16	°C/W
16-Pin Plastic DIP (P)	82	30	°C/W
20-Contact LCC (RC)	98	38	°C/W
16-Pin SO (S)	111	35	°C/W

NOTES:

1. Absolute maximum ratings apply to both DICE and packaged parts, unless otherwise noted.
2. Θ_{JA} is specified for worst case mounting conditions, i.e., Θ_{JA} is specified for device in socket for CerDIP, P-DIP, and LCC packages; Θ_{JA} is specified for device soldered to printed circuit board for SO package.

ELECTRICAL CHARACTERISTICS at V₊ = +15V, V₋ = -15V and T_A = 25°C, unless otherwise noted.

PARAMETER	SYMBOL	CONDITIONS	MUX-08A/E MUX-24A/E			MUX-08B/F MUX-24B/F			UNITS	
			MIN	TYP	MAX	MIN	TYP	MAX		
"ON" Resistance	R _{ON}	V _S ≤ 10V, I _S ≤ 200μA	—	220	300	—	300	400	Ω	
ΔR _{ON} With Applied Voltage	ΔR _{ON}	-10V ≤ V _S ≤ 10V, I _S = 200μA	—	1	5	—	3	7	%	
R _{ON} Match Between Switches	R _{ON} Match	V _S = 0V, I _S = 200μA	—	7	15	—	9	20	%	
Analog Voltage Range	V _A	(Note 6)	+10 -10	+10.4 -15	—	+10 -10	+10.4 -15	—	V	
Source Current (Switch "OFF")	I _{S(OFF)}	V _S = 10V, V _D = -10V (Note 1)	—	0.01	1.0	—	0.01	2.0	nA	
Drain Current (Switch "OFF")	I _{D(OFF)}	V _S = 10V, V _D = -10V (Note 1)	MUX-08	—	0.1	1.0	—	0.1	2.0	nA
			MUX-24	—	0.05	1.0	—	0.05	2.0	
Leakage Current (Switch "ON")	I _{D(ON)} + I _{S(ON)}	V _D = 10V (Note 1)	MUX-08	—	0.1	1.0	—	0.1	2.0	nA
			MUX-24	—	0.05	1.0	—	0.05	2.0	
Digital Input Current	I _{IN}	V _{IN} = 0.4V to 15V	—	1	10	—	1	10	μA	
Digital "0" Enable Current	I _{INL(EN)}	V _{EN} = 0.4V	—	4	10	—	4	10	μA	
Digital Input Capacitance	C _{DIG}		—	3	—	—	3	—	pF	
Switching Time (t _{TRAN})	t _{PHL}	(Notes 2, 5) Figure 1	—	1.5	2.1	—	1.5	2.1	μs	
	t _{PLH}	(Test Circuit)	—	1.0	1.3	—	1.0	1.3		
Output Settling Time	t _S	10V Step to 0.10%	—	2.2	—	—	2.2	—	μs	
		10V Step to 0.05%	—	2.7	—	—	2.7	—		
		10V Step to 0.02%	—	3.4	—	—	3.4	—		
Break-Before-Make Delay	t _{OPEN}	Figure 3 (Test Circuit)	—	0.8	—	—	1.0	—	μs	
Enable Delay "ON"	t _{ON(EN)}	(Note 5) Figure 2 (Test Circuit)	—	1	2	—	1	2	μs	
Enable Delay "OFF"	t _{OFF(EN)}	(Note 5) Figure 2 (Test Circuit)	MUX-08	—	0.1	0.4	—	0.2	0.4	μs
			MUX-24	—	0.2	0.5	—	0.3	0.6	
"OFF" Isolation	ISO _{OFF}	(Note 4) Figure 5 (Test Circuit)	MUX-08	—	60	—	—	60	—	dB
			MUX-24	—	66	—	—	66	—	
Crosstalk	CT	(Note 3) Figure 4 (Test Circuit)	MUX-08	—	70	—	—	70	—	dB
			MUX-24	—	76	—	—	76	—	
Source Capacitance	C _{S(OFF)}	Switch "OFF", V _S = 0V, V _D = 0V	MUX-08	—	2.5	—	—	2.5	—	pF
			MUX-24	—	2	—	—	2	—	
Drain Capacitance	C _{D(OFF)}	Switch "OFF", V _S = 0V, V _D = 0V	MUX-08	—	7	—	—	7	—	pF
			MUX-24	—	4	—	—	4	—	
Input to Output Capacitance	C _{DS(OFF)}	(Note 4)	MUX-08	—	0.3	—	—	0.3	—	pF
			MUX-24	—	0.15	—	—	0.15	—	
Positive Supply Current (All Digital Inputs Logic "0" or "1")	I ₊	V ₊ = 15V	—	10	12	—	6	12	mA	
		V ₊ = 5V	—	8	—	—	5	—		
Negative Supply Current (All Digital Inputs Logic "0" or "1")	I ₋	V ₊ = -15V	—	3.0	3.8	—	2.0	3.8	mA	
		V ₊ = -5V	—	2.5	—	—	1.8	—		

ELECTRICAL CHARACTERISTICS at $V_+ = 15V$, $V_- = -15V$ and $-55^\circ C \leq T_A \leq 125^\circ C$, unless otherwise noted.

PARAMETER	SYMBOL	CONDITIONS	MUX-08A/ MUX-24A			MUX-08B/ MUX-24B			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	
"ON" Resistance	R_{ON}	$V_S \leq 10V$, $I_S \leq 200\mu A$	—	—	400	—	—	500	Ω
ΔR_{ON} With Applied Voltage	ΔR_{ON}	$-10V \leq V_S \leq 10V$, $I_S = 200\mu A$	—	1.5	—	—	4.5	—	%
R_{ON} Match Between Switches	R_{ON} Match	$V_S = 0V$, $I_S = 200\mu A$	—	10	—	—	15	—	%
Analog Voltage Range	V_A	(Note 6)	+10 -10	+10.4 -15	—	+10 -10	+10.4 -15	—	V
Source Current (Switch "OFF")	$I_{S(OFF)}$	$V_S = 10V$, $V_D = -10V$ (Notes 1, 7)	—	—	25	—	—	50	nA
Drain Current (Switch "OFF")	$I_{D(OFF)}$	$V_S = 10V$, $V_D = -10V$ (Notes 1, 7)	MUX-08 MUX-24	—	100	—	—	500	nA
				—	50	—	—	500	
Leakage Current (Switch "ON")	$I_{D(ON)}$ + $I_{S(ON)}$	$V_D = 10V$ (Notes 1, 7)	MUX-08	—	100	—	—	500	nA
			MUX-24	—	50	—	—	500	
Digital "1" Input Voltage	V_{INH}	(Note 6)	2	—	—	2	—	—	V
Digital "0" Input Voltage	V_{INL}	(Note 6)	—	—	0.7	—	—	0.7	V
Digital Input Current	I_{IN}	$V_{IN} = 0.4V$ to $15V$	—	—	20	—	—	20	μA
Digital "0" Enable Current	$I_{INL(EN)}$	$V_{EN} = 0.4V$	—	—	20	—	—	20	μA
Positive Supply Current	I_+	All Digital Inputs Logic "0" or "1"	—	—	15	—	—	15	mA
Negative Supply Current	I_-	All Digital Inputs Logic "0" or "1"	—	—	5	—	—	5	mA

ELECTRICAL CHARACTERISTICS at $V_+ = 15V$, $V_- = -15V$ and $-25^\circ C \leq T_A \leq +85^\circ C$ for MUX-08EQ/FQ and MUX-24EQ/FC
 $0^\circ C \leq T_A \leq +70^\circ C$ for MUX-08EP and MUX-24EP; $-40^\circ C \leq T_A \leq +85^\circ C$ for MUX-08FP/FS and MUX-24FP/FS, unless otherwise noted.

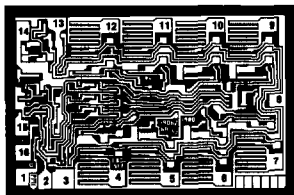
PARAMETER	SYMBOL	CONDITIONS	MUX-08E/ MUX-24E			MUX-08F/ MUX-24F			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	
"ON" Resistance	R_{ON}	$V_S \leq 10V$, $I_S \leq 200\mu A$	—	—	400	—	—	500	Ω
ΔR_{ON} With Applied Voltage	ΔR_{ON}	$-10V \leq V_S \leq 10V$, $I_S = 200\mu A$	—	1.5	—	—	4.5	—	%
R_{ON} Match Between Switches	R_{ON} Match	$V_S = 0V$, $I_S = 200\mu A$	—	10	—	—	15	—	%
Analog Voltage Range	V_A	(Note 6)	+10 -10	+10.4 -15	—	+10 -10	+10.4 -15	—	V
Source Current (Switch "OFF")	$I_{S(OFF)}$	$V_S = 10V$, $V_D = -10V$ (Notes 1, 7)	—	—	10	—	—	10	nA
Drain Current (Switch "OFF")	$I_{D(OFF)}$	$V_S = 10V$, $V_D = -10V$ (Notes 1, 7)	MUX-08 MUX-24	—	100	—	—	100	nA
				—	50	—	—	50	
Leakage Current (Switch "ON")	$I_{D(ON)}$ + $I_{S(ON)}$	$V_D = 10V$ (Notes 1, 7)	MUX-08	—	100	—	—	100	nA
			MUX-24	—	50	—	—	50	
Digital "1" Input Voltage	V_{INH}	(Note 6)	2	—	—	2	—	—	V
Digital "0" Input Voltage	V_{INL}	(Note 6)	—	—	0.8	—	—	0.8	V
Digital Input Current	I_{IN}	$V_{IN} = 0.4V$ to $15V$	—	—	20	—	—	20	μA
Digital "0" Enable Current	$I_{INL(EN)}$	$V_{EN} = 0.4V$	—	—	20	—	—	20	μA
Positive Supply Current	I_+	All Digital Inputs Logic "0" or "1"	—	—	15	—	—	15	mA
Negative Supply Current	I_-	All Digital Inputs Logic "0" or "1"	—	—	5	—	—	5	mA

NOTES:

- Conditions applied to leakage tests insure worst case leakages. Exceeding 11V on the analog input may cause an "OFF" channel to turn "ON".
- $R_L = 10M\Omega$, $C_L = 10pF$.
- Crosstalk is measured by driving channel 8 with channel 4 "ON".
 $R_L = 1M\Omega$, $C_L = 10pF$, $V_S = 5V$ RMS, $f = 500kHz$

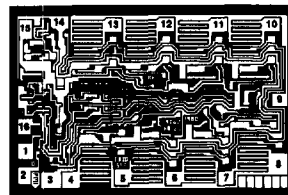
- "OFF" isolation is measured by driving channel 8 with ALL channels "OFF".
 $R_L = 1k\Omega$, $C_L = 10pF$, $V_S = 5V$ RMS, $f = 500kHz$. C_{DS} is computed from t OFF isolation measurement.
- Sample tested.
- Guaranteed by leakage current and R_{ON} tests.
- Leakage tests are performed only on military temperature grades at $125^\circ C$.

DICE CHARACTERISTICS (125°C TESTED DICE AVAILABLE)



MUX-08

MUX-24



DIE SIZE 0.093 × 0.059 inch, 5487 sq. mils
(2.362 × 1.500 mm, 3543 sq. mm)

- | | |
|-------------------|---------|
| 1. A0 | 9. S8 |
| 2. ENABLE | 10. S7 |
| 3. V- (SUBSTRATE) | 11. S6 |
| 4. S1 | 12. S5 |
| 5. S2 | 13. V+ |
| 6. S3 | 14. GND |
| 7. S4 | 15. A2 |
| 8. DRAIN | 16. A1 |

- | | |
|-------------------|------------|
| 1. A0 | 9. DRAIN B |
| 2. ENABLE | 10. S4 B |
| 3. V- (SUBSTRATE) | 11. S3 B |
| 4. S1 A | 12. S2 B |
| 5. S2 A | 13. S1 B |
| 6. S3 A | 14. V+ |
| 7. S4 A | 15. GND |
| 8. DRAIN A | 16. A1 |

For additional DICE ordering information,
refer to 1990/91 Data Book, Section 2.

WAFER TEST LIMITS at $V_+ = 15V$, $V_- = -15V$, $T_A = 25^\circ C$, unless otherwise noted. (Note 1)

PARAMETER	SYMBOL	CONDITIONS	MUX-08/ MUX-24NT LIMIT	MUX-08/ MUX-24N LIMIT	MUX-08/ MUX-24G LIMIT	UNITS
"ON" Resistance	R_{ON}	$V_S = 0V$, $I_S = 200\mu A$, $T_A = 125^\circ C$	300 400	300 —	400 —	Ω MAX
Digital "1" Input Voltage	V_{INH}	(Note 2)	2	2	2	V MIN
Digital "0" Input Voltage	V_{INL}	(Note 2)	0.8	0.8	0.8	V MAX
Digital "0" Input Current	I_{INL}	$V_{IN} = 0.4V$, $T_A = 125^\circ C$	10 20	10 —	10 —	μA MAX
Digital "0" Enable Current	$I_{INL, EN}$	$V_{IN} = 0.4V$, $T_A = 125^\circ C$	10 20	10 —	10 —	μA MAX
Positive Supply Current (All Digital Inputs Logic "0")	I_+	$T_A = 125^\circ C$	12 15	12 —	12 —	mA MAX
Negative Supply Current (All Digital Inputs Logic "0")	I_-	$T_A = 125^\circ C$	3.8 5	3.8 —	3.8 —	mA MAX
Analog Input Range	V_A	(Note 2)	± 10	± 10	± 10	V MIN

NOTE:

Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualification through sample lot assembly and testing.

TYPICAL ELECTRICAL CHARACTERISTICS at $V_+ = 15V$, $V_- = -15V$ and $T_A = 25^\circ C$ for MUX-08/24N & G, $T_A = 125^\circ C$ for MUX-08/24NT, unless otherwise noted.

PARAMETER	SYMBOL	CONDITIONS	MUX-08/ MUX-24NT TYPICAL	MUX-08/ MUX-24N TYPICAL	MUX-08/ MUX-24G TYPICAL	UNITS
Switching Time (t_{TRAN})	t_{PHL} t_{PLH}	(Note 1)	1.7 1.1	1.3 0.9	2.1 1.3	μs
Output Settling Time	t_S	10V Step to 0.1% (Note 1)	2.1	1.5	1.9	μs
Break-Before-Make Delay	t_{OPEN}	(Note 1)	0.8	0.8	1.0	μs
Crosstalk	CT	Note 1	70	70	70	dB
R_{ON} With Applied Voltage	ΔR_{CN}	$-10V \leq V_S \leq 10V$, $I_S = 200\mu A$	2	2	6	%
Package Current (Switch "ON")	$I_{D, ON}$	$V_D = 10V$ (Note 1)	20	0.5	0.5	nA
Analog Input Range	V_A		+10.4/-15	+10.4/-15	+10.4/-15	V

NOTES:

The data shown is extrapolated from measurements made on the packaged devices.

2. Guaranteed by leakage current and R_{ON} tests.

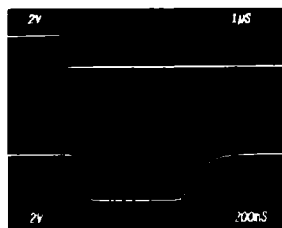
MUX-08
LOGIC STATE

A ₂	A ₁	A ₀	EN	"ON" CHANNEL
X	X	X	L	NONE
L	L	L	H	1
L	L	H	H	2
L	H	L	H	3
L	H	H	H	4
H	L	L	H	5
H	L	H	H	6
H	H	L	H	7
H	H	H	H	8

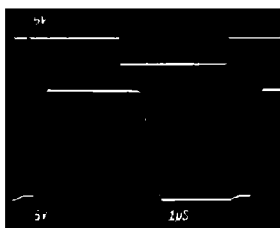
 MUX-24
LOGIC STATE

A ₁	A ₀	EN	"ON" CHANNEL
X	X	L	NONE
L	L	H	1
L	H	H	2
H	L	H	3
H	H	H	4

TYPICAL PERFORMANCE CHARACTERISTICS (Applies to all grades, unless otherwise noted.)

 MUX-08
BREAK-BEFORE-MAKE
SWITCHING


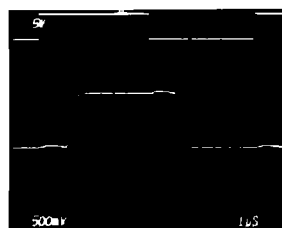
$R_L = 1k\Omega$, $C_L = 10pF$, $V_1 = 10V$
 VOLTAGE = 2V/DIV
 TIME = 200ns/DIV

 MUX-08
LARGE-SIGNAL SWITCHING


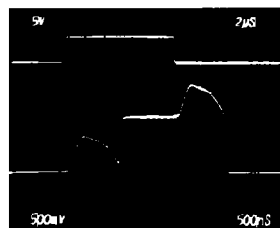
$R_L = 1M\Omega$, $C_L = 10pF$, $V_1 = -10V$, $V_g = +10V$
 VOLTAGE = 5V/DIV
 TIME = 1μs/DIV

 MUX-08
SMALL-SIGNAL SWITCHING


$R_L = 1M\Omega$, $C_L = 10pF$, $V_1 = -500mV$, $V_g = +500mV$
 VOLTAGE = 500mV/DIV
 TIME = 1μs/DIV

 MUX-08
SMALL-SIGNAL SWITCHING
WITH FILTERING


$R_L = 1M\Omega$, $C_L = 500pF$, $V_1 = 500mV$, $V_g = +500mV$
 VOLTAGE = 500mV/DIV
 TIME = 1μs/DIV

 MUX-08
SMALL-SIGNAL SWITCHING
WITH 2μs SAMPLE TIME


$R_L = 1M\Omega$, $C_L = 10pF$, $V_1 = -500mV$, $V_g = +500mV$
 VOLTAGE = 500mV/DIV
 TIME = 500ns/DIV

 MUX-08
SMALL-SIGNAL SWITCHING
WITH FILTERING AND
2.5μs SAMPLE TIME

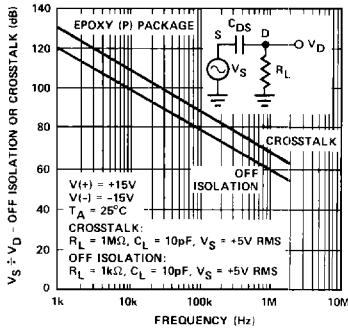

$R_L = 1M\Omega$, $C_L = 500pF$, $V_1 = -500mV$, $V_g = +500mV$
 VOLTAGE = 500mV/DIV
 TIME = 500ns/DIV

NOTE:

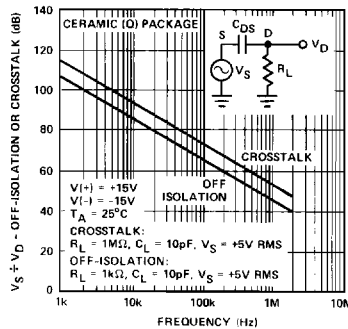
Top waveforms: Digital Input 5V/DIV
 Bottom waveforms: Multiplexer Output

TYPICAL PERFORMANCE CHARACTERISTICS (Applies to all grades, unless otherwise noted.)

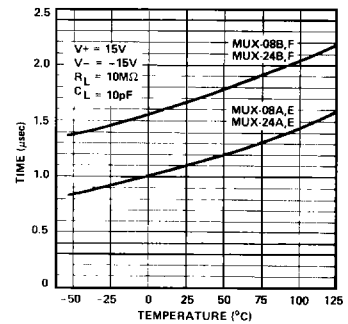
MUX-08 CROSSTALK AND OFF ISOLATION PERFORMANCE OF CHANNEL 8



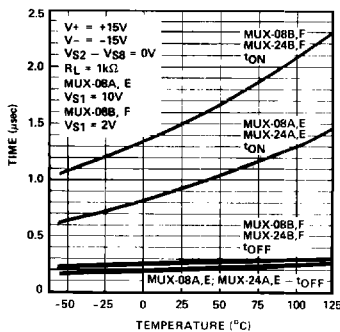
MUX-08 CROSSTALK AND OFF ISOLATION PERFORMANCE OF CHANNEL 8



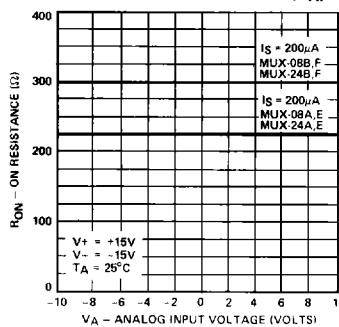
TRANSITION TIMES vs TEMPERATURE



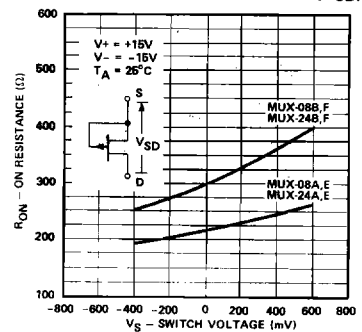
ENABLE DELAY TIMES vs TEMPERATURE



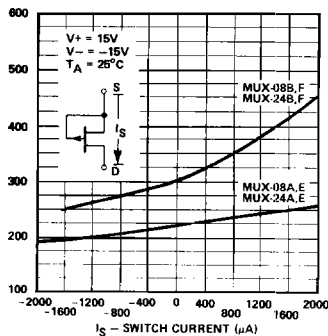
"ON" RESISTANCE (R_{ON}) vs ANALOG VOLTAGE (V_A)



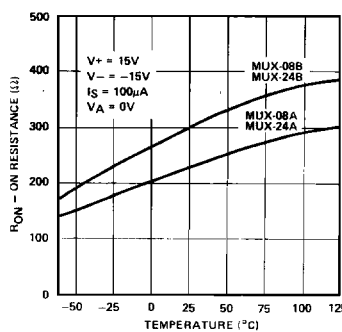
R_{ON} vs SWITCH VOLTAGE (V_{SD})



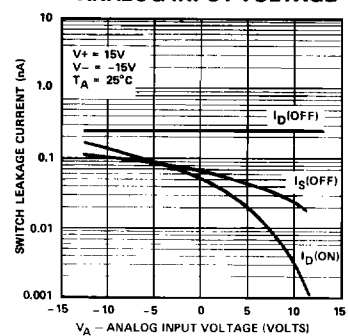
R_{ON} vs SWITCH CURRENT (I_S)



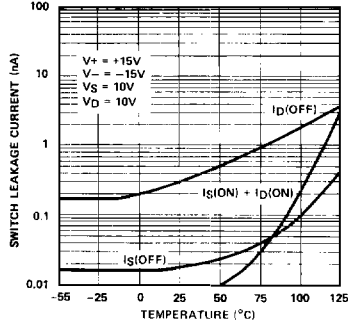
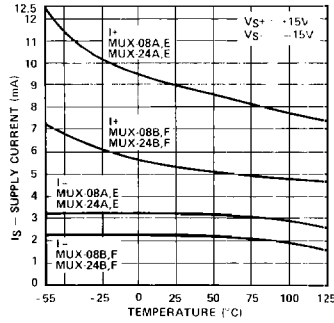
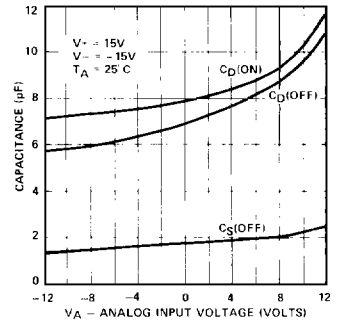
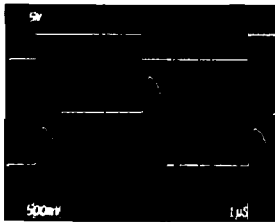
R_{ON} vs TEMPERATURE



SWITCH LEAKAGE CURRENTS vs ANALOG INPUT VOLTAGE



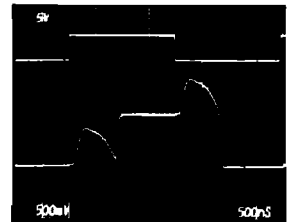
TYPICAL PERFORMANCE CHARACTERISTICS (Applies to all grades, unless otherwise noted.)

 SWITCH LEAKAGE CURRENTS
vs TEMPERATURE

 SUPPLY CURRENTS
vs TEMPERATURE

 MUX-08
SWITCH CAPACITANCES
vs ANALOG INPUT VOLTAGE

 MUX-24
SMALL-SIGNAL SWITCHING


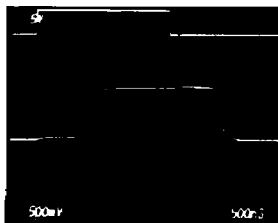
$R_L = 1M\Omega$, $C_L = 10pF$, $V_1 = -500mV$,
 $V_4 = +500mV$
 VOLTAGE = 500mV/DIV, TIME = 1µs/DIV

 MUX-24
SMALL-SIGNAL SWITCHING
WITH FILTERING

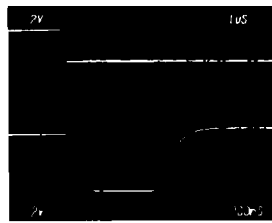

$R_L = 1M\Omega$, $C_L = 500pF$, $V_1 = -500mV$,
 $V_4 = +500mV$
 VOLTAGE = 500mV/DIV, TIME = 1µs/DIV

 MUX-24
SMALL-SIGNAL SWITCHING
WITH 2µs SAMPLE TIME


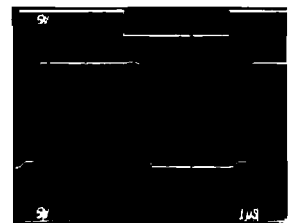
$R_L = 1M\Omega$, $C_L = 10pF$, $V_1 = -500mV$,
 $V_4 = +500mV$
 VOLTAGE = 500mV/DIV, TIME = 500ns/DIV

 MUX-24
SMALL-SIGNAL SWITCHING
WITH FILTERING
AND 2.5µs SAMPLE TIME


$R_L = 1M\Omega$, $C_L = 500pF$, $V_1 = -500mV$,
 $V_4 = +500mV$
 VOLTAGE = 500mV/DIV, TIME = 500ns/DIV

 MUX-24
BREAK-BEFORE-MAKE
SWITCHING


$R_L = 1k\Omega$, $C_L = 10pF$, $V_1 = 4 = 10V$
 VOLTAGE = 2V/DIV, TIME = 200ns/DIV

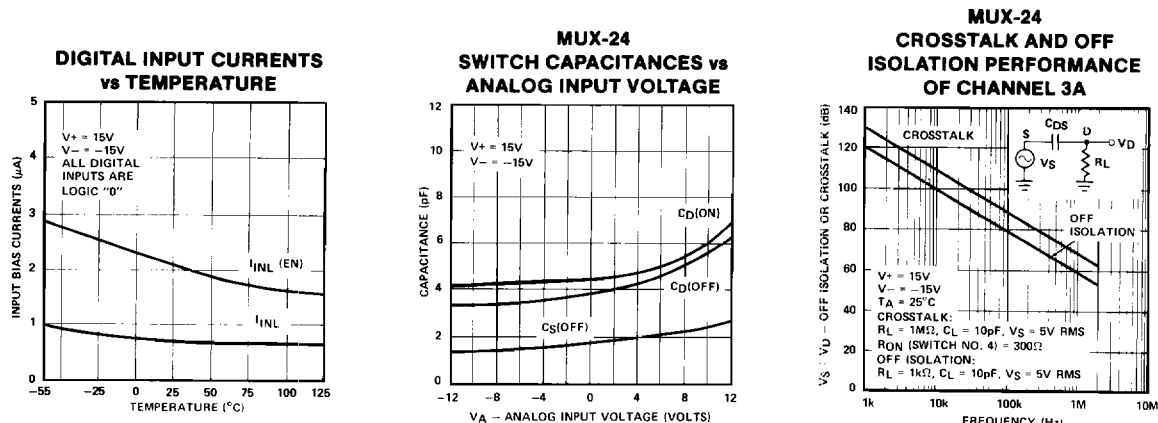
 MUX-24
LARGE-SIGNAL SWITCHING


$R_L = 1M\Omega$, $C_L = 10pF$, $V_1 = -10V$, $V_4 = +10V$
 VOLTAGE = 5V/DIV, TIME = 1µs/DIV

NOTE:

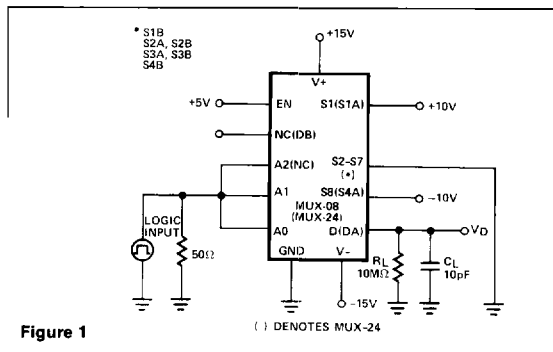
Top waveforms: Digital Input 5V/DIV
 Bottom waveforms: Multiplexer Output

TYPICAL PERFORMANCE CHARACTERISTICS (Applies to all grades, unless otherwise noted.)

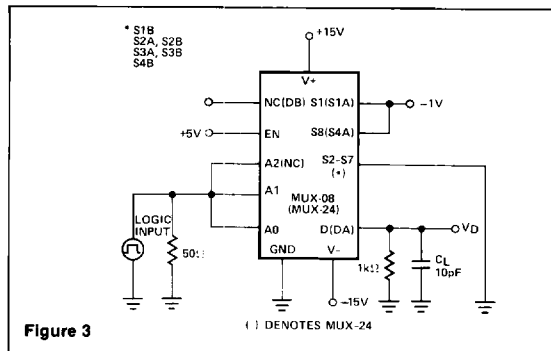


A.C. TEST CIRCUITS

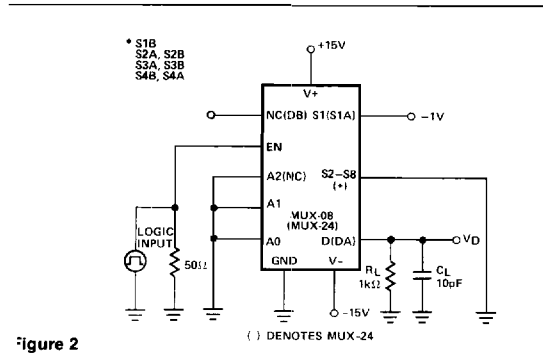
TRANSITION TIME TEST CIRCUIT



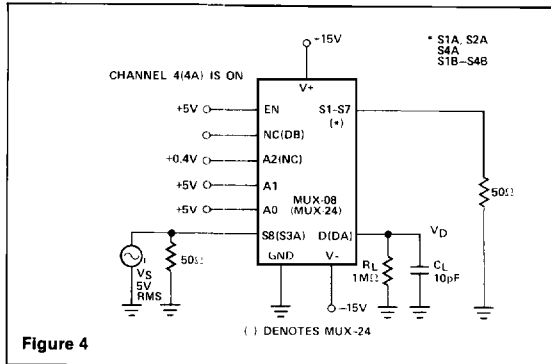
BREAK-BEFORE-MAKE TEST CIRCUIT



RISE/FALL DELAY TIME TEST CIRCUIT

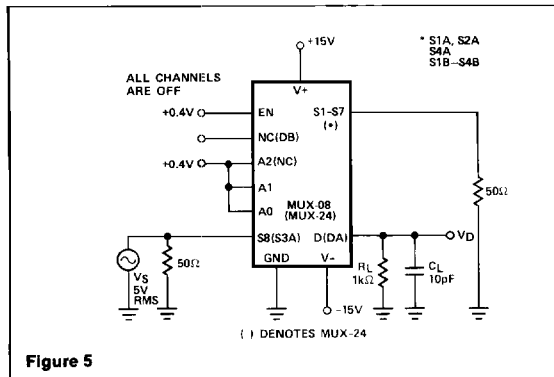


CROSSTALK MEASUREMENT CIRCUIT

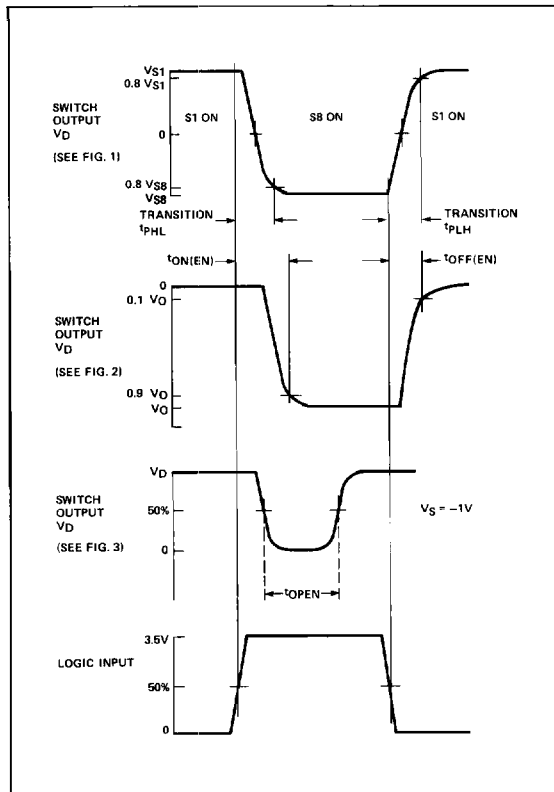


A.C. TEST CIRCUITS

OFF-ISOLATION MEASUREMENT CIRCUIT



SWITCHING TIME WAVEFORMS



APPLICATIONS INFORMATION

These analog multiplexers employ ion-implanted JFETs in a switch configuration designed to assure break-before-make action. The turn-off time is much faster than the turn-on time to guarantee this feature over the full operating temperature and input voltage range. Fabricated with Bipolar-JFET processing, **special handling as required with CMOS devices, is not necessary to prevent damage to this multiplexer.** Because the digital inputs only require a 2.0V logic "1" input level, power-consuming pull-up resistors are not required for TTL compatibility to insure break-make switching as is most often the case with CMOS multiplexers. The digital inputs utilize PNP input transistors where input current is maximum at the logic "0" level and drops to that of a reverse-biased diode (about 10nA) as the input voltage is raised above $\approx 1.4V$.

The "ON" resistance, R_{ON} , of the analog switches is constant over the wide input voltage range of $-15V$ to $+11V$ with $V_{SUPPLY} = \pm 15V$. Higher input voltage is tolerable provided that some form of current limiting is employed (such as that of an op-amp output stage) to avoid exceeding junction temperature and power dissipation requirements. For normal operation, however, positive input voltages should be restricted to 11V (or 4V less than the positive supply). This assures that the V_{GS} of an "OFF" switch remains greater than its V_p and prevents that channel from being falsely turned "ON". When operating with negative input voltages, the gate-to-channel diode will be turned on if the voltage drop across an "ON" switch exceeds $-0.6V$. While this condition will cause an error in the output, it will not damage the switch. In lab tests, the multiplexer output has been loaded with $0.01\mu F$ capacitor in the circuit of Figure 1. With $V_1 = -10V$ and $V_2 = +10V$, the logic input was driven at a 1kHz rate. The positive-going slew rate was $0.3V/\mu s$ which is equivalent to normal I_{DSS} of 3mA. The negative-going slew rate was $0.7V/\mu s$ which is equivalent to a "reverse" I_{DSS} of 7mA. Note that when switch 1 is first turned "ON" it has a drop of -20 across its terminals. In spite of that fact, the current is limited to approximately twice its normal I_{DSS} .

CROSSTALK AND OFF-ISOLATION

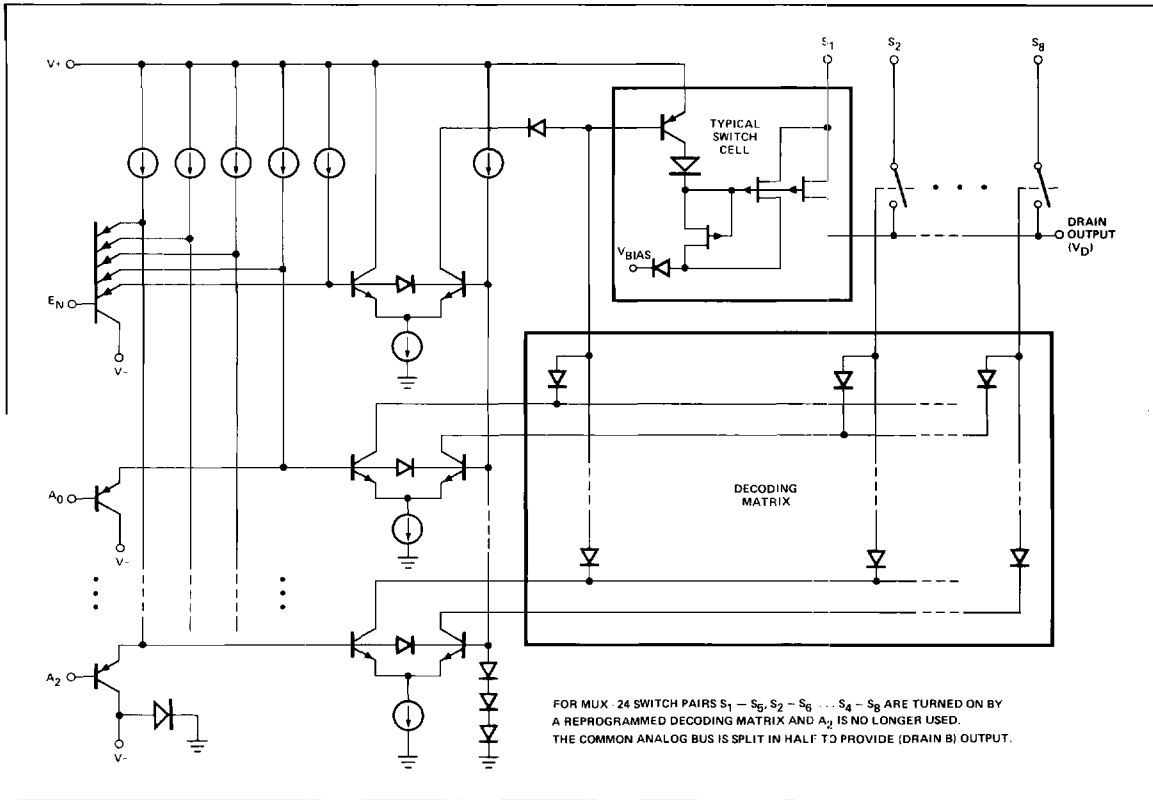
Crosstalk and off-isolation performance is influenced by the type of package selected. Epoxy (P) packaged devices typically exhibit a 12dB improvement in off-isolation ($f = 500kHz$) performance when compared to ceramic (C) packaged devices. Epoxy packaged devices typically exhibit a 15dB improvement in crosstalk ($f = 500kHz$) performance when compared to ceramic (Q) packaged devices.

SINGLE SUPPLY OPERATION OF JFET MULTIPLEXERS

PMI's JFET multiplexers will operate from a single positive supply voltage with the negative supply pin at ground potential. The analog signal range will include ground.

For complete single supply operation information, refer application note, AN-32.

SIMPLIFIED MUX-08 SCHEMATIC



The simplified MUX-08/MUX-24 schematic shows that logic input points are determined by two forward diode drops. An internal clamping diode between V^- and ground prevents excessive current flow between V^+ and ground in the event at V^- becomes open circuit. The decoding matrix is accomplished by a programmed diode array. The switch cell consists of P channel JFET's with appropriate blocking codes which ruggedizes the circuit's overvoltage and supply characteristics.

DIFFERENTIAL MULTIPLEXERS

A characteristic unique to differential multiplexers (MUX-24) is the ability to reject common-mode signals from coming differential error signals. Common-mode rejection is a parameter which defines the amount of rejection in terms dB. The MUX-24 exhibits a 106dB at 60Hz and 101dB at 10Hz of CMRR using the test circuit of Figure 6.

CMRR TEST CIRCUIT

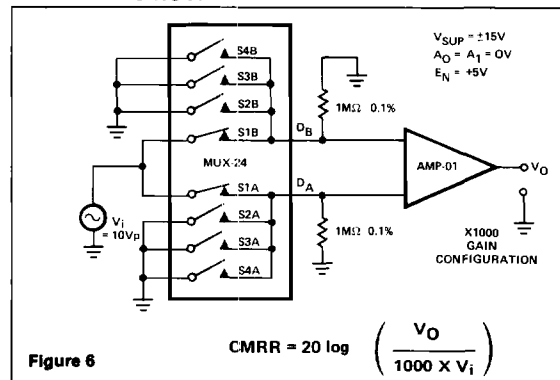
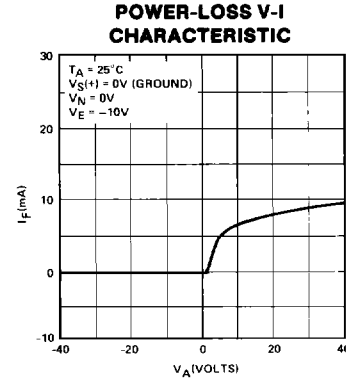
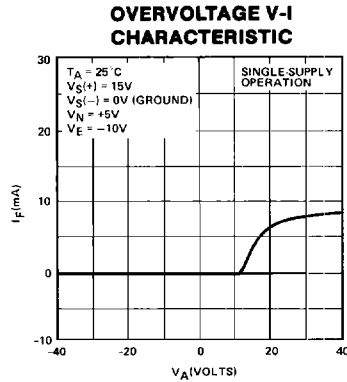
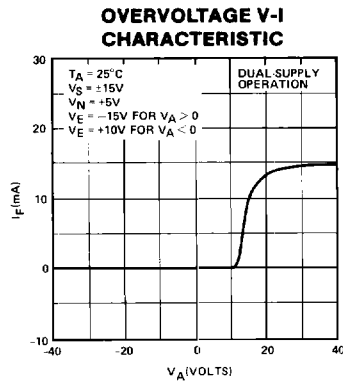


Figure 6

TYPICAL PERFORMANCE CHARACTERISTICS



OVERVOLTAGE/POWER-LOSS MEASUREMENT TEST CIRCUIT

